

MagneticMulti75-G

AFM Tip

SHAPE	HEIGHT	SETBACK	RADIUS	HALF CONE ANGLE
Rotated	17 μm (15 – 19 μm)*	15 μm (10 – 20 μm)*	60 nm	20°–25° along cantilever axis, 25°–30° from side, 10° at the apex

AFM Cantilever

Cantilever A	
Shape	Beam
Force Constant	3 N/m (1 – 7 N/m)*
Resonance Frequency	75 kHz (60 – 90 kHz)*
Length	225 μm (215 – 235 μm)*
Width	28 μm (23 – 33 μm)*
Thickness	3 μm (2 – 4 μm)*

* typical range

Coating

Hard magnetic, medium momentum coating on tip side of the cantilever and aluminium reflex coating on detector side of the cantilever

Alignment Grooves

This product features alignment grooves on the back side of the holder chip.

Additional Info

Monolithic silicon AFM probe for magnetic force microscopy (MFM). The cobalt alloy coated AFM tip has a magnetic moment of roughly 10^{-13} emu and coercivity of roughly 300 Oe.

The rotated AFM tip allows for more symmetric representation of high sample features. The consistent AFM tip radius ensures good resolution and reproducibility.

The AFM holder chip fits most commercial AFM systems as it is industry standard size.